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## NTE907 Integrated Circuit Diode Array

**Description:**

The NTE907 consists of six ultra-fast, low capacitance diodes on a common monolithic substrate. Five of the diodes are independently accessible, with the sixth sharing a common terminal with the substrate. The NTE907 comes in a 12-Lead TO5 type package.

**Features:**

- Excellent Reverse Recovery Time: 1ns typ.
- Matched Monolithic Construction:  $V_F$  matched within 5mV
- Low Diode Capacitance:  $C_D = 0.65\text{pF}$  typical at  $V_R = -2\text{V}$

**Applications:**

- Balanced Modulators or Demodulators
- Ring Modulators
- High Speed Diode Gates
- Analog Switches

**Absolute Maximum Ratings:** ( $T_A = +25^\circ\text{C}$  unless otherwise specified)

Power Dissipation, $P_D$	
Any one diode unit	100mW
Total for device	600mW
For $T_A > 55^\circ\text{C}$	derate linearly 5.7mW/ $^\circ\text{C}$
Operating Temperature Range, $T_{opr}$	$-55^\circ$ to $+125^\circ\text{C}$
Storage Temperature Range, $T_{stg}$	$-65^\circ$ to $+150^\circ\text{C}$
Peak Inverse Voltage, $P_{IV}$	
$D_1 - D_5$	5V
$D_6$	0.5V
Peak Diode-to-Substrate Voltage, $V_{DI}$	
for $D_1-D_5$ (Pin1, 4, 5, 8, or 12 to Pin10)	+20V, -1V
DC Forward Current, $I_F$	25mA
Peak Recurrent Forward Current, $I_F$	100mA
Peak Forward Surge Current, $I_F$ (Surge)	100mA
Lead Temperature, $T_L$	
(During soldering 1/16 $\pm$ 1/32" (1.59 $\pm$ 0.79mm) from case for 10sec Max)	+265 $^\circ\text{C}$

**Electrical Characteristics:** ( $T_A = +25^\circ\text{C}$ , Note 1 unless otherwise specified)

Parameter	Symbol	Test Conditions	Min	Typ	Max	Unit
DC Forward Voltage Drop	$V_F$	$I_F = 50\mu\text{A}$	–	0.65	0.69	V
		$I_F = 1\text{ mA}$	–	0.73	0.78	
		$I_F = 3\text{mA}$	–	0.76	0.80	
		$I_F = 10\text{mA}$	–	0.81	0.90	
DC Reverse Breakdown Voltage	$V_{(BR)R}$	$I_R = -10\mu\text{A}$	5	7	–	V
DC Reverse Breakdown Voltage Between any Diode Unit and Substrate	$V_{(BR)R}$	$I_R = -10\mu\text{A}$	20	–	–	V
DC Reverse (Leakage) Current	$I_R$	$V_R = -4\text{V}$	–	0.016	100	nA
DC Reverse (Leakage) Current Between any Diode Unit and Substrate	$I_R$	$V_R = -10\text{V}$	–	0.022	100	nA
Magnitude of Diode Offset Voltage (Difference in DC Forward Voltage Drops of any Two Diode Units)	$ V_{F1}-V_{F2} $	$I_F = 1\text{mA}$	–	0.5	5	mV
Temperature Coefficient of $ V_{F1}-V_{F2} $	$\frac{\Delta V_{F1}-V_{F2} }{\Delta T}$	$I_F = 1\text{mA}$	–	1	–	$\mu\text{V}/^\circ\text{C}$
Temperature Coefficient of Forward Drop	$\frac{\Delta V_F}{\Delta T}$	$I_F = 1\text{mA}$	–	-1.9	–	$\text{mV}/^\circ\text{C}$
DC Forward Voltage Drop for Anode-to-Substrate Diode ( $D_S$ )	$V_F$	$I_F = 1\text{mA}$	–	0.65	–	V
Reverse Recovery Time	$t_{rr}$	$I_F = 10\text{mA}, I_R = 10\text{mA}$	–	1	–	ns
Diode Resistance	$R_D$	$f = 1\text{kHz}, I_F = 1\text{mA}$	25	30	45	$\Omega$
Diode Capacitance	$C_D$	$V_R = -2\text{V}, I_F = 0$	–	0.65	–	pF
Diode-to-Substrate Capacitance	$C_{D1}$	$V_{D1} = +4\text{V}, I_F = 0$	–	3.2	–	pF

Note 1. Characteristics apply for each diode unit, unless otherwise specified.



